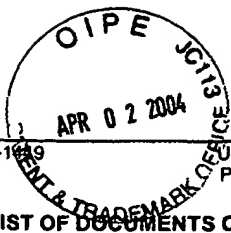


Sheet 1 of 2

FORM PTO-149 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-987	SERIAL NO. 09/869,274			
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT A. NISHIMURA et al				
				FILING DATE June 26, 2001	GROUP			
U.S. PATENT DOCUMENTS								
* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)	
	AA	6,030,890	2/29/00	Iwabuchi				
	AB	6,008,543	12/28/99	Iwabuchi				
	AC	9,994,940	9/10/96	Hubacher				
	AD							
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
FOREIGN PATENT DOCUMENTS								
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
OC	AL	4-26537	3/3/92	Japan			<input type="checkbox"/>	<input type="checkbox"/>
OC	AM	4-96343	3/27/92	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AN	5-218042	8/27/93	Japan			<input type="checkbox"/>	<input type="checkbox"/>
OC	AO	8-250498	9/27/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AP	8-64633	3/8/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)								
	AR	IEEE/CPMT INTL ELECTRONICS MANUFACTURING TECHNOLOGY SYMPOSIUM, "Impact of Wafer Probe Damage on Flip Chip Yields and Reliability", M. Varnau et al, pp. 293-297.						
	AS							
	AT							
EXAMINER <i>Old Chandra</i>				DATE CONSIDERED <i>August 25, 2004</i>				



FORM PTO-159 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-987		SERIAL NO. 09/869,274	
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT A. NISHIMURA et al			
				FILING DATE June 26, 2001		GROUP	
U.S. PATENT DOCUMENTS							
* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
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	OC AM	8-29451	2/2/96	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AN						<input type="checkbox"/> <input type="checkbox"/>
	AO						<input type="checkbox"/> <input type="checkbox"/>
	AP						<input type="checkbox"/> <input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	AR						
	AS						
	AT						
EXAMINER <i>Ohl Changhwa</i>				DATE CONSIDERED <i>August 25, 2004</i>			